

**Search Notes**

Application/Control No.

10/776,616

Examiner

Hien X. Vo

Applicant(s)/Patent under  
Reexamination

KOKUBO ET AL.

Art Unit

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	151	6/2/2006	VXH
	142		
	44		
73	117.3		
	195		
	862.08		
	862.338		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/2/2006	VXH
	6/6/2006	